


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509201	<b>Applicant(s)/Patent Under Reexamination</b>  MOON, SEUNG-HWAN
	<b>Examiner</b>  Mandeville, Jason M	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner
345	38, 55, 87-100, 102, 104, 214-215	27 April 2007	Jason Mandeville
345	38, 55, 87-100, 102, 104, 214-215	11/20/2007	Jason Mandeville
345	55-111, 545, 560, 211-213	16 May 2008	Jason Mandeville
345	55-111, 545, 560, 211-213	12/05/2008	Jason Mandeville
345	55-111, 545, 560, 211-213	18 May 2009	Jason Mandeville

SEARCH NOTES		
Search Notes	Date	Examiner
Searched US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB	27 April 2007	Jason Mandeville
Searched US-PGPUB, USPAT, USOCR FPRS, EPO, JPO, DERWENT, IBM_TDB	11/20/2007	Jason Mandeville
Inventor Search	11/20/2007	Jason Mandeville
Searched US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB	16 May 2008	Jason Mandeville
Inventor Search	16 May 2008	Jason Mandeville
Searched US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB	12/05/2008	Jason Mandeville
Inventor Search	12/05/2008	Jason Mandeville
Searched US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB	18 May 2009	Jason Mandeville
Inventor Search	18 May 2009	Jason Mandeville

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
/J. M. M./ Examiner.Art Unit 2629			

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/J. M. M./ Examiner.Art Unit 2629	
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